

Integration and Test Strategies for Complex Manufacturing Machines

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de Jong, I. 2008. *Integration and Test Strategies for Complex Manufacturing Machines: Integration and Testing Combined in a Single Planning and Optimization Framework*. Saarbrücken, Germany: Verlag.

Usage

This source is considered a primary reference for the Business Activities Related to Product Systems Engineering articles.

Annotation

This PhD thesis research project goal is to reduce the duration of the integration and test phase of large complex embedded systems. It uses a Wafer Scanner as an example. The work was performed at the Embedded Systems Institute in Eindhoven.

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